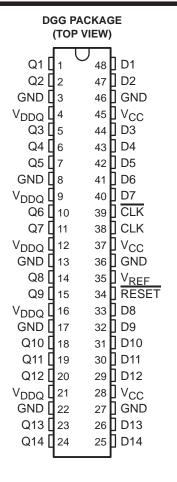


- Supports SSTL_2 Signal Data Inputs and Outputs
- Supports LVTTL Switching Levels on the RESET Pin
- Differential CLK Signal
- Flow-Through Architecture Optimizes PCB Layout
- Meets SSTL_2 Class II Specifications
- Latch-Up Performance Exceeds 100 mA Per JESD 78, Class II
- ESD Protection Exceeds JESD 22
 - 2000-V Human-Body Model (A114-A)
 - 200-V Machine Model (A115-A)
 - 1000-V Charged-Device Model (C101)
- Packaged in Plastic Thin Shrink Small-Outline Package

description

This 14-bit registered buffer is designed for 2.3-V to 3.6-V V_{CC} operation and SSTL_2 data input and output levels.

All inputs are compatible with the JEDEC Standard for SSTL_2, except the LVCMOS reset (RESET) input. All outputs are SSTL_2, Class II compatible.



When RESET is low, the differential input receivers are disabled, and undriven (floating) data and clock inputs are allowed. In addition, when RESET is low, all registers are reset, and all outputs are forced low. The LVCMOS RESET input must always be held at a valid logic high or low level.

To ensure defined outputs from the register before a stable clock has been supplied, RESET must be held in the low state during power up.

The SN74SSTL16857 is characterized for operation from 0°C to 70°C.

FUNCTION TABLE (each flip-flop)

	OUTPUT			
RESET	CLK	CLK	D	Q
L	Х	Χ	Χ	L
Н	\downarrow	\uparrow	Н	Н
Н	\downarrow	\uparrow	L	L
Н	L or H	L or H	Χ	Q_0

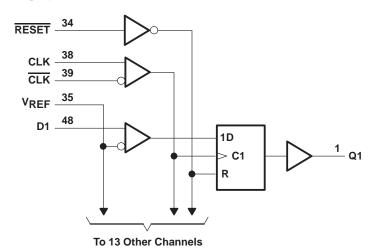


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logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC} or V _{DDQ}	
Input voltage range, V _I (see Note 1)	0.5 V to V _{DDQ} + 0.5 V
Output voltage range, VO (see Notes 1 and 2)	0.5 V to V _{DDQ} + 0.5 V
Input clamp current, $I_{ K }(V_{ C } < 0)$	
Output clamp current, I _{OK} (V _O < 0)	
Continuous output current, I_O ($V_O = 0$ to V_{DDQ})	±50 mA
Continuous current through each VCC, VDDQ, or GND	±100 mA
Package thermal impedance, θ _{JA} (see Note 3)	
Storage temperature range, T _{Stg}	

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

- 2. Current flows only when the output is in the high state and $V_O > V_{DDQ}$.
- 3. The package thermal impedance is calculated in accordance with JESD 51.



SCAS625C - FEBRUARY 1999 - REVISED OCTOBER 1999

recommended operating conditions (see Note 4)

			MIN	NOM	MAX	UNIT
Vcc	Supply voltage		V_{DDQ}		3.6	V
V _{DDQ}	Output supply voltage		2.3		2.7	V
VREF	Reference voltage (V _{REF} = V _{DDQ} /2)		1.15	1.25	1.35	V
VTT			V _{REF} -40 mV	V _{REF}	V _{REF} +40 mV	V
VI	Input voltage		0		VCC	V
VIH	AC high-level input voltage	Data inputs	V _{REF} +350 mV			V
VIL	AC low-level input voltage	Data inputs			V _{REF} -350 mV	V
VIH	DC high-level input voltage	Data inputs	V _{REF} +180 mV			V
VIL	DC low-level input voltage Data inputs				V _{REF} -180 mV	V
VIH	High-level input voltage RESET		2			V
V _{IL}	Low-level input voltage	RESET			0.8	V
VICR	Common-mode input voltage range	CLK, CLK	0.97		1.53	V
V _{I(PP)}	Peak-to-peak input voltage	CLK, CLK	360			mV
ІОН	High-level output current				-20	mA
loL	Low-level output current				20	mA
TA	Operating free-air temperature		0		70	°C

NOTE 4: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.

SCAS625C - FEBRUARY 1999 - REVISED OCTOBER 1999

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST C	TEST CONDITIONS		MIN	TYP	MAX	UNIT		
VIK		I _I = -18 mA		2.3 V			-1.2	V		
		I _{OH} = -100 μA	I _{OH} = -100 μA		V _{CC} -0.2					
Vон		I _{OH} = -8 mA	I _{OH} = -8 mA		1.95			V		
		I _{OH} = -16 mA		2.3 V	1.95					
		I _{OL} = 100 μA	I _{OL} = 100 μA				0.2			
V_{OL}		$I_{OL} = 8 \text{ mA}$		2.3 V			0.35	V		
		I _{OL} = 16 mA		2.3 V			0.35			
		V _I = 1.7 V or 0.8V	V 445 V and 25 V	0.7.1/	±5					
	Data innuta	V _I = 2.7 V or 0	V _{REF} = 1.15 V or 1.35 V	2.7 V			±5			
	Data inputs	V _I = 1.7 V or 0.8V	V _{REF} = 1.15 V or 1.35 V	2.21/			±5	μΑ		
		V _I = 2.7 V or 0		3.6 V			±5			
ΙΙ	CLK, CLK	V _I = 1.7 V or 0.8V	V _{REF} = 1.15 V or 1.35 V	2.7 V			±1			
		V _I = 2.7 V or 0					±1			
		V _I = 1.7 V or 0.8V	V=== 1 15 V or 1 25 V	3.6 V			±1	mA		
		V _I = 2.7 V or 0	V _{REF} = 1.15 V or 1.35 V				±1			
	DECET V	V. Van or CND	V _I = V _{CC} or GND				±5	μΑ		
	RESET	AI = ACC OL GMD					±5			
	V	V=== 4.45 V or 4.25 V	V 4.45 V on 4.25 V				±5			
VREF		VREF = 1.15 V OF 1.35 V	V _{REF} = 1.15 V or 1.35 V				±5	1		
		V _I = 1.7 V or 0.8 V	1- 0	2.7 V	90					
	$V_{I} = 2.7 \text{ V or } 0$	I _O = 0		90			^			
^I cc		V _I = 1.7 V or 0.8 V	la 0	3.6 V			90	mA		
		V _I = 2.7 V or 0	IO = 0	3.6 V	90			<u> </u>		
0.	RESET	V: 47Vor09V	V _I = 1.7 V or 0.8 V			3		pF		
	Data inputs	V = 1.7 V 01 0.0 V				2.5				
Ci	RESET	\/ı = 1.7\/ or 0.9\/	V: 47V 2*0 8 V			3		PΓ		
Data inputs		V = 1.7 V UI U.0 V	V _I = 1.7 V or 0.8 V			2.5				

[†] All typical values are at $V_{CC} = 2.5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figure 1)

		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 3.3 V ± 0.3 V		UNIT	
			MIN	MAX	MIN	MAX	
fclock	f _{clock} Clock frequency			150		150	MHz
t _W	t _W Pulse duration, CLK, CLK high or low		3.3		3.3		ns
	t _{SU} Setup time	Data before CLK↑, CLK↓	1.1		1.75		20
^t su		RESET high before CLK↑, CLK↓	0.6		1.1		ns
th	Hold time, data after CLK↑, CLK↓		0.7		0.7		ns



[‡] All typical values are at $V_{CC} = 3.3 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

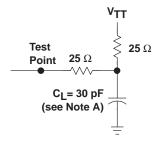
SN74SSTL16857 14-BIT SSTL_2 REGISTERED BUFFER

SCAS625C - FEBRUARY 1999 - REVISED OCTOBER 1999

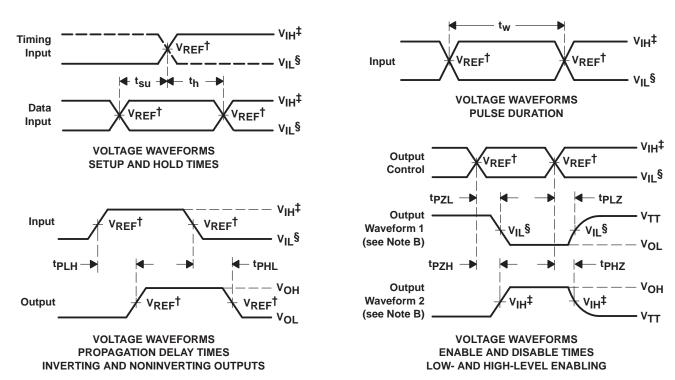
switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	MAX	MIN	MAX	
f _{max}			150		150		MHz
^t pd	CLK and CLK	Q	1.5	3.8	1.4	3.7	ns
^t PHL	RESET	Q	1.5	4.3	1.4	3.5	ns

PARAMETER MEASUREMENT INFORMATION V_{CC} = 2.5 V \pm 0.2 V AND V_{CC} = 3.3 V \pm 0.3 V



LOAD CIRCUIT



 $^{^{\}dagger}V_{REF} = V_{DDQ}/2$

NOTES: A. C_I includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z_O = 50 Ω , $t_f \leq$ 1.25 ns/V, $t_f \leq$ 1.25 ns/V.
- D. The outputs are measured one at a time with one transition per measurement.
- E. $V_{TT} = V_{REF} = V_{DDQ}/2$
- F. tpLZ and tpHZ are the same as tdis.
- G. tpzL and tpzH are the same as ten.
- H. tpLH and tpHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms



[‡]V_{IH} = V_{REF} + 350 mV (AC voltage levels)

[§] VIL = VREF - 350 mV (AC voltage levels)

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